

Application/Control No.	Applicant(s)/Patent under Reexamination
10/798,133	ONOUE ET AL.
Examiner	Art Unit
Benjamin Kurtz	1723

	SEAR	CHED	<u>,</u>
Class	Subclass	Date	Examiner
210	232,233 238,435 443,444	5/8/2006	ВК

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
East Search	5/8/2006	вк	
Inventor Name Search	5/8/2006	вк	